

# 7 S.W.H. 7/11/02

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219527US2S DIV		SERIAL NO. New Divisional Application		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT						
		FILING DATE Herewith		GROUP				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<i>HN</i>	AA	5,687,160	11/97	Aotake et al.	—	—		
<i>HN</i>	AB	5,731,852	03/98	Lee	—	—		
<i>HN</i>	AC	6,185,365	02/01	Murase et al.	—	—		
<i>HN</i>	AD	6,067,400	05/00	Saeki et al.	—	—		
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION			
HN	AO	7-143429	06-02-95	JAPAN	YES	NO	X	
	AP							
	AQ							
	AR							
	AS							
	AT							
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner	<i>HUY NGUYEN</i>				Date Considered <i>4/18/03</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT	ATTY DOCKET NO. 219527US-2S DIV	SERIAL NO. 10/076,277
		APPLICANT Hideo ANDO et al.	
		FILING DATE February 19, 2002	GROUP 2615

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Ha</i>	AA	5,712,947	27 Jan 1998	Oguro et al.	—	—	
<i>ky</i>	AB	6,148,138	14 Nov 2000	Sawabe et al.	—	—	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
<i>Ha</i>	AO	JP 5-158778	25 Jun 1993	Japan	x	
<i>ky</i>	AP	JP 5-165935	2 July 1993	Japan	x	
<i>ky</i>	AQ	JP 7-143429	2 Jun 1995	Japan (with Statement of Relevancy)		x
<i>ky</i>	AR	JP 8-205014	9 Aug 1996	Japan	x	
<i>ky</i>	AS	JP 9-182013	11 July 1997	Japan	x	
<i>ky</i>	AT	JP 11-136613	21 May 1999	Japan	x	
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>ky</i>	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00201476 (with English Translation).
<i>ky</i>	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09804370 (with English Translation).
<i>ky</i>	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09904199 (with English Translation).
	AZ	

Examiner	<i>HUY NGUYEN</i>	Date Considered
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LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Hideo ANDO, et al	
		FILING DATE		GROUP	
		02/19/02		2615	

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA	AA	6,385,389	7 May 2002	Maruyama et al.	—	—	RECEIVED
AB	AB						OCT 10 2002
AC	AC						Technology Center 2600
AD	AD	OCT 09 2002					
AE	AE						
AF	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
AG	AG	EP 1 065 665 A1	03 Jan 2001	EPO (In English)		
AH	AH	JP 5-81787	2 Apr 1993	JAPAN	X	
AI	AI	JP 8-106721	23 Apr 1996	JAPAN	X	
AJ	AJ	JP 9-259539	3 Oct 1997	JAPAN	X	
AK	AK	JP 11-215471	6 Aug 1999	JAPAN		X
AL	AL	JP 11-238362	31 Aug 1999	JAPAN		X
AM						
AN						
AO						
AP						
AQ						
AR						

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AS	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English Translation).
AT	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English Translation).
AU	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English Translation).
AV	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English Translation).
AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English Translation).
AX	
AY	
AZ	

Examiner <i>HVY Nov 03</i>	Date Considered <i>4/18/03</i>
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